

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:  
Barber et al.

) Docket No.: 20.2895

)

)

Serial No.: 10/707,813

) Group Art Unit:

)

Filed: January 14, 2004

) Confirmation:

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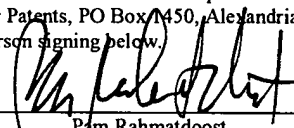
For: Apparatus and Methods for Determining Isotropic and  
Anisotropic Formation Resistivity in the Presence of Invasion

) Examiner:

)

CERTIFICATE OF MAILING

I hereby certify that this correspondence (along with any document referenced as being attached or enclosed hereto) is being deposited with the United States Postal Service in an envelope as First Class Mail addressed to: Commissioner for Patents, PO Box 1450, Alexandria VA 22313-1450 on this date by the person signing below.

  
Pam Rahmatdoost

1/16/04  
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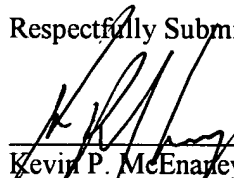
INFORMATION DISCLOSURE STATEMENT

Dear Sir:

The following documents on the Form PTO-1449 are submitted to the United States Patent and Trademark Office under provisions of 37 CFR 1.97-1.98. A copy of each reference is enclosed.

Please charge any necessary fees to the deposit account for Schlumberger Technology Corporation, Account No. 19-0610.

Respectfully Submitted,



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Date:

Jan 16, 2004

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Schlumberger Private

FORM PTO-1449 (Modified)

LIST OF INFORMATION PROVIDED  
BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.  
20.2895SERIAL NO.  
10/707,813

APPLICANT: Barber et al.

FILING DATE:  
January 14, 2004

GROUP

## REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Patentee
	AA			
	AB			
	AC			
	AD			
	AE			
	AF			
	AG			
	AH			
	AI			

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation Yes No	
	AJ					
	AM					
	AN					
	AO					

## OTHER INFORMATION PROVIDED (AUTHOR, TITLE, DATE, PLACE OF PUBLICATION, PERTINENT PAGES, ETC.)

AR	Hunka et al., "A New Resistivity Measurement System for Deep Formation Imaging and High-Resolution Formation Evaluation," SPE 20559, 65 <sup>th</sup> Annual Technical Conference and Exhibition, New Orleans LA, September 23-26, 1990 (pp. 295-307)
AS	Moran et al., "Effects of Formation Anisotropy on Resistivity-Logging Measurements," Geophysics, Vol. 44, NO. 7 (July 1979) pp. 1266 - 1286
AT	Amderson et al., "The Response of Induction Tools to Dipping, Anisotropic Formations," SPWLA 36 <sup>th</sup> Annual Logging Symposium, June 26 - 29, 1995, Paper D

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior art to the subject invention.
2. This is not a representation that a search has been made.

FORM PTO-1449 (Modified)

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## REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Patentee
	BA			
	BB			
	BC			
	BD			
	BE			
	BF			
	BG			
	BH			
	BI			

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation Yes No	
	BL					
	BM					
	BN					
	BO					

## OTHER INFORMATION PROVIDED (AUTHOR, TITLE, DATE, PLACE OF PUBLICATION, PERTINENT PAGES, ETC.)

BR	Anderson et al., "The Effect of Crossbedding Anisotropy on Induction Tool Response," SPWLA 39 <sup>th</sup> Annual Logging Symposium, May 26-29, 1998, Keystone, CO, Paper B
BS	Davydycheva et al., "An Efficient Finite-Difference Scheme for Electromagnetic Logging in 3D Anisotropic Inhomogeneous Media," Geophysics Vo. 68, No. 5 (September - October 2003) pp. 1525-1536.
BT	

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